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Meet Tomorrow's Challenges with Nanoscale Expertise

Environmental Monitoring Products for Electronics and Semiconductor

Airborne Particle Counters

10 nm to 25 µm measurement

Models for every electronics and semiconductor environment and application including:

- Cleanroom monitoring
- Tool monitoring
- Gas monitoring
- Nano LPM[™] System
 UPW Contamination Monitoring
 - Reliable 10 nm detection of particulate and dissolved contamination in UPW.
 - Integrated injection port for onsite performance verification
- AeroTrak™+ Remote
 Particle Counters
 Ultra-Reliable Data Collection
 - Protect against network failures with six months of data storage
 - Flexible environmental monitoring system with Wi-Fi® communication
- Aerosol Sampling Manifold

 Monitor up to 32 points with a single
- particle counter

 High Pressure Diffusers
 - Measure particulate contamination in high-pressure compressed gas systen
- 5 AeroTrak™+ Portable Particle Counters
 - Different sample modes for monitoring, classifying, and root cause investigation
 - Built-in monitoring and classification reports
- AeroTrak[™] Handheld Particle Counters
- 7 Integrated Environmental Monitoring Probes
 - Using FMS
- AeroTrak™ Cleanroom Condensation Particle Counter
 - Confident 24/7 operation
 - Minimal maintenance
 - High flow rates
 - Ultra-low false count rates
 - No contamination or chemicals introduced into the ultra-clean environment

TSI° Facility Monitoring Software: Reliable Monitoring Systems

FMS Architecture

Distributed. Flexible. Redundant.

- No single point of failure
- Data available where and when you need it
- · Easily scalable

C S Monitor:

- Data CollectionFault-tolerant design
- Protects against network failures
- Hot-standby options

B Client: Interface

- Turn data into knowledge with alarming, reports, and trending
- Does not effect monitor or database functions
- Access anywhere with FMS Web Client

Database: Secure Storage

- Valuable data is safe and secure
- Redundancy is standard with a mirror database
- SQL for high availability and fast access



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Particle and Environmental Monitoring Products for Electronics and Semiconductor

Facility Monitoring System

A reliable monitoring system that supports process control and decreases downtime.

Minimum Particle Size

Remote Particle Counters

Designed for continuous monitoring as part of the Facility Monitoring System

with Analog and WiFi options

0.1 CFM (2.83 LPM) flow rate, includes AeroTrak™+ 6000 series 0.2 μm onboard pump, compact size, many

communications options

0.1 CFM (2.83 LPM) and 1 CFM (28.3 AeroTrak™+ 7000 series 0.2 μm LPM) flow rate, compact size, many

communications options

1 CFM (28.3 LPM) flow rate, internal pump, 0.3 to 5.0 channels available, field-removable AeroTrak™+ 6310 0.3 um

1 CFM (28.3 LPM) flow rate, complies with all ISO 21501-4 requirements AeroTrak™ 7110 0.1 um (100 nm)

Portable Particle Counters

AeroTrak™+ A100 Series 0.3 μm

Versatile instruments suitable for classification and monitoring

1 CFM (28.3 LPM), 1.77 CFM (50 LPM), and 3.53 CFM (100 LPM) flow rate models available, intuitive interface, simplifies sampling with workflows, built-in classification and monitoring reporting capabilities, gas and filter testion.

and filter testing

1 CFM (28.3 LPM) flow rate, includes display and onboard pump, provides classification testing, complies with all ISO 21501-4 AeroTrak™ 9110 0.1 µm (100 nm)

Handheld Particle Counters

Economical choice for higher class cleanrooms and investigations

0.1 CFM (2.83 LPM) flow rate, 3 channels of simultaneous data, small, lightweight, AeroTrak™ 9303 0.3 µm

versatile, low cost

0.1 CFM (2.83 LPM) flow rate, 6 channels AeroTrak™ 9306 0.3 µm of simultaneous data, versatile

Cleanroom Condensation Particle Counter

The only water-based, laminar flow CPC on the market that can run continuously, 24/7, or as a standalone unit

Nano LPM™ System

AeroTrak Cleanroom 0.1 CFM (2.83 LPM) flow rate, ultralow zero 0.01 µm (10 nm) counts for cleanroom processes

Nanoparticle Monitoring in Ultrapure Water (10 nm)
Empowers data-driven decisions in UPW monitoring...like never before.

0.01 µm (10 nm)

Detects solid and dissolved contamination >10 nm using nebulization and a specialized cleanroom condensation particle counter.





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